

IE3100R System Design Project

Enhancing Spares Cost estimation for the material planning department with an automated Cost Per Wafer (CPW) calculator



It involves scheduling routine

Problem Description

At Micron Technology, Inc., estimating the Cost per Wafer (CPW) for spare parts-a critical yet manual process-posed significant challenges. The manual calculation was not only time-consuming but also prone to errors, making the task of budget estimation for material procurement each quarter laborious and inefficient. This process, susceptible to human error, hindered quick adaptability to changes, increasing the workload and affecting the accuracy essential for the Material Planning Team's operations.

Recognising the need for a transformative solution, the project aimed to automate the CPW calculation process. This strategic shift was designed to enhance precision, reduce manual effort, and support Micron's commitment to operational excellence and costeffective manufacturing.

PM CPW Calculator

PM Data prepartation via SQL

 Data Extracted from BOM(PM, cycle, Qty per PM, Unit cost, Micron P/N, WS, Technical identification no)

2.RPT data from MFG dry etch portal dashboard given by

MFG



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PM Results Analysis									
Technode	Sum of CPW (Automated)	Sum of CPW (Manual)	Delta	% Delta					
100s	19.67	22.96	-3.30	-14.36					
110s	26.11	31.03	-4.92	-15.87					
120s	28.89	29.99	-1.10	-3.67					
140s	12.96	12.95	0.01	0.08					
PM CPW +									



Despite the overall success, there were variances in some calculations. 97.59% of these discrepancies were traced back to differences in chamber count values from 3 workstation data. 2.41% was due to manual adjustment on other columns of data.

Results Analysis

CM Results Analysis							
Technodes	Sum of CPW (Automated)		Sum of CPW (Manual)		Delta	% Delta	
100s	24.97		26.20		1.23	4.68%	
110s	33.86		30.70		-3.16	-10.29%	
120s	40.82		38.70		-2.12	-5.48%	
140s	17.76		15.10		-2.66	-17.6%	
Technode	Delta	%	Delta	Variance Reasoning			
100s	-3.30	-	14.36	m actual 15 for 4			
110s	-4.92	-15.87		Manually adjusted ESC (40-50) &			
120s	-1.10	-3.67		Agile Unit (1->6) for 10-3TEL_VIGSRK4_0X_06MERCON			
140s	0.01		0.08				

Variances are explained by the manual adjustment of parts used by the Manufacturing Team as they predict the machines' efficiency from the past data.

1. Data frames are merged together and aggregated to get a data frame of Expense data quantity and costs for each part. The quantity and costs are multiplied to obtain the total CM Costs CM parts1 2. The life time for 1 each CM part is CM Costs CM Lifetime obtained from manufacturing's data CM cost per min **RPT** in min CM CPW source

3. The CM cost per minute is obtained by dividing the total CM cost with the lifetime for each part

4. Raw Processing Time (RPT) in minutes is obtained from the manufacturing data source and multiplied with the CM cost per minute to get the CM CPW

CM Misssing Data Checks

Missing data rows and entries are compiled based on the 'Cost per RF Minute', 'Raw Processing Time' and 'Work Station'.

Future Improvements

Understanding

Manual

Adjustments

Proactive Inclusion of Adjustments in Automation

Missing data validation check

Past Trend Analysis

1.Quarter to quarter CpW Comparison to look for fluctuation 2.Automated variance commentary

Cost Forecasting

1.Quantify more factors that contribute to the change in CpW 2.Simulation of budget expenses for different loading scenarios

The team proposed to forecast the Cost per Wafer by using different regression models such as linear regression, polynomial regression and ridge regression. However, we were advised that there are more factors affecting future forecasting, some of which are difficult to be quantified.